

Application/Control No.	Applicant(s)/Patent under Reexamination
09/926,241	ARIMURA, TAKUYA
Examiner	Art Unit
Hanh Nguyen	2668

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	235	9/22/05	AM
	311		
	320		
	321		
	329		
	<i>35</i> 0		
	412		
	पा९		
	420		
375	324		
	316		
	325		
	147		
	240.24		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
370	335	9/22/05	HN		
	413	•			
375	325				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East	9/22/05	HN		